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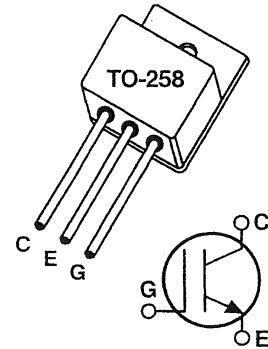
APT33GF120HR

1200V 38A

## Fast IGBT

The Fast IGBT is a new generation of high voltage power IGBTs. Using Non-Punch Through Technology the Fast IGBT offers superior ruggedness, fast switching speed and low Collector-Emitter On voltage.

- Low Forward Voltage Drop
- Low Tail Current
- Avalanche Rated
- Hermetic Package
- High Freq. Switching to 20KHz
- Ultra Low Leakage Current
- RBSOA and SCSOA Rated



### MAXIMUM RATINGS

All Ratings:  $T_C = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	APT33GF120HR	UNIT
$V_{CES}$	Collector-Emitter Voltage	1200	Volts
$V_{CGR}$	Collector-Gate Voltage ( $R_{GE} = 20K\Omega$ )	1200	
$V_{GE}$	Gate-Emitter Voltage	$\pm 20$	
$I_{C1}$	Continuous Collector Current @ $T_C = 25^\circ\text{C}$	38	Amps
$I_{C2}$	Continuous Collector Current @ $T_C = 90^\circ\text{C}$	33	
$I_{CM}$	Pulsed Collector Current <sup>①</sup> @ $T_C = 25^\circ\text{C}$	76	
$I_{LM}$	RBSOA Clamped Inductive Load Current @ $R_g = 11\Omega$ $T_C = 125^\circ\text{C}$	66	
$E_{AS}$	Single Pulse Avalanche Energy <sup>②</sup>	65	mJ
$P_D$	Total Power Dissipation	205	Watts
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$T_L$	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300	

### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$BV_{CES}$	Collector-Emitter Breakdown Voltage ( $V_{GE} = 0V, I_C = 0.8mA$ )	1200			Volts
$V_{GE(TH)}$	Gate Threshold Voltage ( $V_{CE} = V_{GE}, I_C = 700\mu A, T_J = 25^\circ\text{C}$ )	4.5	5.5	6.5	
$V_{CE(ON)}$	Collector-Emitter On Voltage ( $V_{GE} = 15V, I_C = I_{C2}, T_J = 25^\circ\text{C}$ )		2.7	3.2	
	Collector-Emitter On Voltage ( $V_{GE} = 15V, I_C = I_{C2}, T_J = 125^\circ\text{C}$ )		3.3	3.9	
$I_{CES}$	Collector Cut-off Current ( $V_{CE} = V_{CES}, V_{GE} = 0V, T_J = 25^\circ\text{C}$ )			0.8	mA
	Collector Cut-off Current ( $V_{CE} = V_{CES}, V_{GE} = 0V, T_J = 125^\circ\text{C}$ )			5.0	
$I_{GES}$	Gate-Emitter Leakage Current ( $V_{GE} = \pm 20V, V_{CE} = 0V$ )			$\pm 100$	nA

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

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## DYNAMIC CHARACTERISTICS

APT33GF120HR

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
$C_{ies}$	Input Capacitance	<b>Capacitance</b> $V_{GE} = 0V$ $V_{CE} = 25V$ $f = 1\text{ MHz}$		1850		pF
$C_{oes}$	Output Capacitance			200		
$C_{res}$	Reverse Transfer Capacitance			110		
$Q_g$	Total Gate Charge <sup>③</sup>	<b>Gate Charge</b> $V_{GE} = 15V$ $V_{CC} = 0.5V_{CES}$ $I_C = I_{C2}$		165		nC
$Q_{ge}$	Gate-Emitter Charge			20		
$Q_{gc}$	Gate-Collector ("Miller") Charge			100		
$t_d(\text{on})$	Turn-on Delay Time	<b>Resistive Switching (25°C)</b> $V_{GE} = 15V$ $V_{CC} = 0.8V_{CES}$ $I_C = I_{C2}$ $R_G = 10\Omega$		30		ns
$t_r$	Rise Time			140		
$t_d(\text{off})$	Turn-off Delay Time			150		
$t_f$	Fall Time			200		
$t_d(\text{on})$	Turn-on Delay Time	<b>Inductive Switching (150°C)</b> $V_{CLAMP}(\text{Peak}) = 0.66V_{CES}$ $V_{GE} = 15V$ $I_C = I_{C2}$ $R_G = 10\Omega$ $T_J = +150^\circ\text{C}$		28		ns
$t_r$	Rise Time			60		
$t_d(\text{off})$	Turn-off Delay Time			280		
$t_f$	Fall Time			30		
$E_{on}$	Turn-on Switching Energy			3.0		
$E_{off}$	Turn-off Switching Energy		3.0			
$E_{ts}$	Total Switching Losses		6.0			
$t_d(\text{on})$	Turn-on Delay Time	<b>Inductive Switching (25°C)</b> $V_{CLAMP}(\text{Peak}) = 0.66V_{CES}$ $V_{GE} = 15V$ $I_C = I_{C2}$ $R_G = 10\Omega$ $T_J = +25^\circ\text{C}$		28		ns
$t_r$	Rise Time			70		
$t_d(\text{off})$	Turn-off Delay Time			250		
$t_f$	Fall Time			25		
$E_{ts}$	Total Switching Losses			5.0		
$g_{fe}$	Forward Transconductance	$V_{CE} = 20V, I_C = I_{C2}$	8.5	20		S

## THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.61	°C/W
$R_{\theta JA}$	Junction to Ambient			40	

① Repetitive Rating: Pulse width limited by maximum junction temperature.

②  $I_C = I_{C2}$ ,  $R_{GE} = 25\Omega$ ,  $L = 119\mu\text{H}$ ,  $T_J = 25^\circ\text{C}$

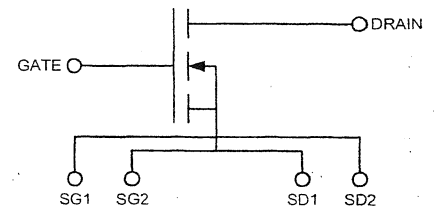
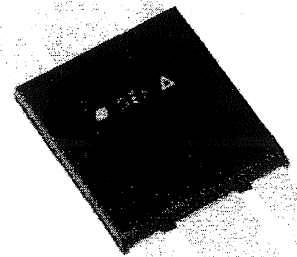
③ See MIL-STD-750 Method 3471

APT Reserves the right to change, without notice, the specifications and information contained herein.

- ◆ N-Channel Enhancement Mode
- ◆ Low  $Q_g$  and  $R_g$
- ◆ High  $dv/dt$
- ◆ Nanosecond Switching
- ◆ 30MHz Maximum Frequency

$V_{DSS} = 1000\text{ V}$   
 $I_{D25} = 24\text{ A}$   
 $R_{DS(on)} = 0.41\ \Omega$   
 $P_{DC} = 1500\text{ W}$

Symbol	Test Conditions	Maximum Ratings	
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	1000	V
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GS} = 1\text{ M}\Omega$	1000	V
$V_{GS}$	Continuous	$\pm 20$	V
$V_{GSM}$	Transient	$\pm 30$	V
$I_{D25}$	$T_c = 25^\circ\text{C}$	24	A
$I_{DM}$	$T_c = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	144	A
$I_{AR}$	$T_c = 25^\circ\text{C}$	21	A
$E_{AR}$	$T_c = 25^\circ\text{C}$	30	mJ
$dv/dt$	$I_s \leq I_{DM}$ , $di/dt \leq 100\text{ A}/\mu\text{s}$ , $V_{DD} \leq V_{DSS}$ , $T_J \leq 150^\circ\text{C}$ , $R_G = 0.2\ \Omega$	5	V/ns
	$I_s = 0$	>200	V/ns
$P_{DC}$		1500	W
$P_{DHS}$	$T_c = 25^\circ\text{C}$ Derate $4.0\text{ W}/^\circ\text{C}$ above $25^\circ\text{C}$	600	W
$P_{DAMB}$	$T_c = 25^\circ\text{C}$	4.5	W
$R_{thJC}$		0.10	$^\circ\text{C}/\text{W}$
$R_{thJHS}$		0.2	$^\circ\text{C}/\text{W}$



**Symbol Test Conditions Characteristic Values**  
 $T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Test Conditions	min.	typ.	max.
$V_{DSS}$	$V_{GS} = 0\text{ V}$ , $I_D = 3\text{ ma}$	1000		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 4\text{ ma}$	2.5		5.5 V
$I_{GSS}$	$V_{GS} = \pm 20\text{ V}_{DC}$ , $V_{DS} = 0$			$\pm 100\text{ nA}$
$I_{DSS}$	$V_{DS} = 0.8\text{ V}_{DSS}$ , $T_J = 25^\circ\text{C}$ $V_{GS} = 0$ , $T_J = 125^\circ\text{C}$			50 $\mu\text{A}$
				1 mA
$R_{DS(on)}$	$V_{GS} = 15\text{ V}$ , $I_D = 0.5I_{D25}$ Pulse test, $t \leq 300\ \mu\text{s}$ , duty cycle $d \leq 2\%$			0.41 $\Omega$
$g_{fs}$	$V_{DS} = 15\text{ V}$ , $I_D = 0.5I_{D25}$ , pulse test		27	S
$T_J$		-55		+175 $^\circ\text{C}$
$T_{JM}$			175	$^\circ\text{C}$
$T_{stg}$		-55		+175 $^\circ\text{C}$
$T_L$	1.6mm (0.063 in) from case for 10 s		300	$^\circ\text{C}$
<b>Weight</b>			3	g

**Features**

- Isolated Substrate:
  - high isolation voltage (>2500V)
  - excellent thermal transfer
  - increased temperature and power cycling capability
- IXYS advanced low  $Q_g$  process
- Low gate charge and capacitances
  - easier to drive
  - faster switching
- Low  $R_{DS(on)}$
- Very low insertion inductance (<2nH)
- No beryllium oxide (BeO) or other hazardous materials

**Advantages**

- Optimized for RF and high speed switching at frequencies to 30MHz
- Easy to mount—no insulators needed
- High power density

